

A new testability calculation method to guide RTL test generation

Raik, Jaan; Nõmmeots, Tanel; Ubar, Raimund-Johannes Journal of electronic testing : theory and applications 2005 / 1, p. 71-82 : ill <https://link.springer.com/article/10.1007/s10836-005-5288-5>

Design error diagnosis with re-synthesis in combinational circuits

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High-Level Implementation-Independent Functional Software-Based Self-Test for RISC Processors

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On the reuse of TLM mutation analysis at RTL

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PSL assertion checking using temporally extended high-level decision diagrams

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